TECHNOLOGY & STIRING TECHNOLOG

Requistition Form

Bruker D8Advance X-Ray Diffractometer Central Sophisticated Instrumentation Facility (CSIF)

BITS Pilani K K Birla Goa Campus, Zuarinagar, GOA – 403720, India.

User Name:	, UIN:		
Whether sampling modalitie	s & Requirements are discussed w	ith the operator (Y/N):_	
Sample Description Powder / Pellet / Thin film			
Analysis Details			
2 O range			
Scanning rate (Degree/min)			
completely fill the circular Time Required: Payment Details:	should be submitted in the form of cavity of the sample holder. hrs. :		
Total Amount Paid: Rs.			/
Undertaking:			
preparation guidelines and prec CSIF will not be responsible fo we agree not to make any claim	SIF BITS PILANI K K Birla Goa (ng sample preparation/ana	lysis and in such cases I/
Signature of the user	nature of the user Signature of the Supervisor/HC		f the Supervisor/HOD
For Accounts Section:			
Amount Received: Rs.	/-, Voucher No:	, Date:	, Signature with Seal